Ultramicroscopy 38 (1991) 363–364
North-Holland

ultramicroscopy

Author index to volume 38

Ai, R., see Dunn 38 (1991) 333
Ai, R., see Marks 38 (1991) 343
Allison, D.P., see Brown 38 (1991) 253
Aoki, Y., see Fujiyoshi 38 (1991) 241

Barhatzky, H., see Cline 38 (1991) 299
Beltrán del Río, L., A. Gómez and M. José-Yacamán, Image processing in TEM using the wavelet transform 38 (1991) 319
Bentley, J., see Wang 38 (1991) 181
Bentzon, M.D. and A.R. Thölén, Phase contrast from a regular stacking of equally sized iron-oxide spheres 38 (1991) 105
Brown, G.M., D.P. Allison, R.J. Warmack, K.B. Jacobson, F.W. Larimer, R.P. Woychik and W.L. Carrier, Electrochemically induced adsorption of radio-labeled DNA on gold and HOPG substrates for STM investigations 38 (1991) 253
Brown, L.M., see Browning 38 (1991) 291
Browning, N.D., J. Yuan and L.M. Brown, Real-space determination of anisotropic electronic structure by electron energy loss spectroscopy 38 (1991) 291

Carrier, W.L., see Brown 38 (1991) 253
Cerva, H., see Thoma 38 (1991) 265
Chapon, C., see Giorgio 38 (1991) 1
Chen, F.Y.Y., see Egerton 38 (1991) 349
Chiu, D.K.Y., see Harauz 38 (1991) 305
Cline, J.A., H. Barhatzky and M. Isaacson, Scanned-tip reflection-mode near-field scanning optical microscopy 38 (1991) 299
Coene, W.M.J. and T.J.J. Denteneer, Improved methods for the determination of the spherical aberration coefficient in high resolution electron microscopy from micrographs of an amorphous object 38 (1991) 225
Crowther, R.A., see Taylor 38 (1991) 85

Daberkow, I., K.-H. Herrmann, L. Liu and W.D. Rau, Performance of electron image converters with YAG single-crystal screen and CCD sensor 38 (1991) 215
D'Antonio, P., see Konnert 38 (1991) 169
De Jong, A.F., see Koster 38 (1991) 235
Denteneer, T.J.J., see Coene 38 (1991) 225
Dorset, D.L., Is electron crystallography possible? The direct determination of organic crystal structures 38 (1991) 23
Dorset, D.L., W.F. Tivol and J.N. Turner, Electron crystallography at atomic resolution: ab initio structure analysis of copper perchlorophthalocyanine 38 (1991) 41
Duan, X.F., see Fung 38 (1991) 143
Dunn, D.N., R. Ai, T.S. Savage, J.P. Zhang and L.D. Marks, Preparation and detection of reconstructed plan-view surfaces 38 (1991) 333
Dürr, R., Displacement field analysis: calculation of distortion measures from displacement maps 38 (1991) 135

Egerton, R.F., Y.-Y. Wang and F.Y.Y. Chen, EELS of "thick" specimens 38 (1991) 349

Fujiyoshi, Y., T. Mizusaki, K. Morikawa, H. Yamagishi, Y. Aoki, H. Kihara and Y. Harada, Development of a superfluid helium stage for high-resolution electron microscopy 38 (1991) 241
Fung, K.K., Q.H. Xie and X.F. Duan, Convergent-beam electron diffraction study of modulations in semiconductor superlattices 38 (1991) 143

Giorgio, S., C.R. Henry, C. Chapon, G. Nihoul and J.M. Penisson, Electron-beam-induced transformations of gold particles epitaxially grown on MgO microcubes 38 (1991) 1
Gómez, A., see Beltrán del Río 38 (1991) 319

Harada, Y., see Fujiyoshi 38 (1991) 241
Harauz, G. and D.K.Y. Chiu, Covering events in eigenimages of biomolecules 38 (1991) 305
Hawkes, P.W., New books and journals 38 (1991) 353
Henry, C.R., see Giorgio 38 (1991) 1
Herrmann, K.-H., see Daberkow 38 (1991) 215
Hofer, F. and B. Luo, Towards a practical method for EELS quantification 38 (1991) 159
Hunt, J.A. and D.B. Williams, Electron energy-loss spectrum-imaging 38 (1991) 47

Isaacson, M., see Cline 38 (1991) 299

Elsevier Science Publishers B.V.

Jacobson, K.B., see Brown 38 (1991) 253
Jonas, P. and P. Schattschneider, Electron Compton scattering with parallel detection: an experiment with very low count rates 38 (1991) 117
José-Yacamán, M., see Beltrán del Río 38 (1991) 319

Kihara, H., see Fujiyoshi 38 (1991) 241
Konnert, J. and P. D'Antonio, Utilization of STEM nanodiffraction data 38 (1991) 169
Koster, A.J. and A.F. de Jong, Measurement of the spherical aberration coefficient of transmission electron microscopes by beam-tilt-induced image displacements 38 (1991) 235

Larimer, F.W., see Brown 38 (1991) 253
Leapman, R., Report of a meeting 38 (1991) 361
Lichte, H., Optimum focus for taking electron holograms 38 (1991) 13
Liu, L., see Daberkow 38 (1991) 215
Loane, R.F., see Xu 38 (1991) 127
Luo, B., see Hofer 38 (1991) 159

Marks, L.D., Rigor, and plan-view simulation of surfaces 38 (1991) 325
Marks, L.D., see Dunn 38 (1991) 333
Marks, L.D., T.S. Savage, J.P. Zhang and R. Ai, Validity of the kinematical approximation in transmission electron diffraction for surfaces, revisited 38 (1991) 343
McCaffrey, J.P., Small-angle cleavage of semiconductors for transmission electron microscopy 38 (1991) 149
Mizusaki, T., see Fujiyoshi 38 (1991) 241
Morikawa, K., see Fujiyoshi 38 (1991) 241

Nihoul, G., see Giorgio 38 (1991) 1

Penisson, J.M., see Giorgio 38 (1991) 1

Rau, W.D., see Daberkow 38 (1991) 215

Savage, T.S., see Dunn 38 (1991) 333
Savage, T.S., see Marks 38 (1991) 343
Schattschneider, P., see Jonas 38 (1991) 117
Silcox, J., see Xu 38 (1991) 127

Taylor, K.A. and R.A. Crowther, A protocol for 3D image reconstruction from a single image of an oblique section 38 (1991) 85
Thölén, A.R., see Bentzon 38 (1991) 105
Thoma, S. and H. Cerva, New methods for qualitative and quantitative analysis of the GaAs/AlGaAs interface by high-resolution electron microscopy 38 (1991) 265
Tivol, W.F., see Dorset 38 (1991) 41
Turner, J.N., see Dorset 38 (1991) 41

Van Heel, M., A fast algorithm for transposing large multidimensional image data sets 38 (1991) 75

Wang, Y.-Y., see Egerton 38 (1991) 349
Wang, Z.L. and J. Bentley, Theory of phase correlations in localized inelastic electron diffraction and imaging 38 (1991) 181
Warmack, R.J., see Brown 38 (1991) 253
Williams, D.B., see Hunt 38 (1991) 47
Woychik, R.P., see Brown 38 (1991) 253

Xie, Q.H., see Fung 38 (1991) 143
Xu, P., R.F. Loane and J. Silcox, Energy-filtered convergent-beam electron diffraction in STEM 38 (1991) 127

Yamagishi, H., see Fujiyoshi 38 (1991) 241
Yuan, J., see Browning 38 (1991) 291

Zhang, J.P., see Dunn 38 (1991) 333
Zhang, J.P., see Marks 38 (1991) 343

Ultramicroscopy 38 (1991) 365–367
North-Holland

ultramicroscopy

Subject index to volume 38

Detectors, photographic and other
Performance of electron image converters with YAG single-crystal screen and CCD sensor, *Daberkow, Herrmann, Liu and Rau* 38 (1991) 215

Diffraction and optical diffraction
Is electron crystallography possible? The direct determination of organic crystal structures, *Dorset* 38 (1991) 23
Electron crystallography at atomic resolution: ab initio structure analysis of copper perchlorophthalocyanine, *Dorset, Tivol and Turner* 38 (1991) 41
Energy-filtered convergent-beam electron diffraction in STEM, *Xu, Loane and Silcox* 38 (1991) 127
Convergent-beam electron diffraction study of modulations in semiconductor superlattices, *Fung, Xie and Duan* 38 (1991) 143
Utilization of STEM nanodiffraction data, *Konnert and D'Antonio* 38 (1991) 169
Theory of phase correlations in localized inelastic electron diffraction and imaging, *Wang and Bentley* 38 (1991) 181
Validity of the kinematical approximation in transmission electron diffraction for surfaces, revisited, *Marks, Savage, Zhang and Ai* 38 (1991) 343

Electron energy loss spectroscopy
Electron energy-loss spectrum-imaging, *Hunt and Williams* 38 (1991) 47
Electron Compton scattering with parallel detection: an experiment with very low count rates, *Jonas and Schattschneider* 38 (1991) 117
Energy-filtered convergent-beam electron diffraction in STEM, *Xu, Loane and Silcox* 38 (1991) 127
Towards a practical method for EELS quantification, *Hofer and Luo* 38 (1991) 159
Theory of phase correlations in localized inelastic electron diffraction and imaging, *Wang and Bentley* 38 (1991) 181
Real-space determination of anisotropic electronic structure by electron energy loss spectroscopy, *Browning, Yuan and Brown* 38 (1991) 291
EELS of "thick" specimens, *Egerton, Wang and Chen* 38 (1991) 349
Report of a meeting, *Leapman* 38 (1991) 361

High resolution
Phase contrast from a regular stacking of equally sized iron-oxide spheres, *Bentzon and Thölén* 38 (1991) 105
New methods for qualitative and quantitative analysis of the GaAs/AlGaAs interface by high-resolution electron microscopy, *Thoma and Cerva* 38 (1991) 265

Image processing, 3D reconstruction
Is electron crystallography possible? The direct determination of organic crystal structures, *Dorset* 38 (1991) 23
A fast algorithm for transposing large multidimensional image data sets, *Van Heel* 38 (1991) 75
A protocol for 3D image reconstruction from a single image of an oblique section, *Taylor and Crowther* 38 (1991) 85
Covering events in eigenimages of biomolecules, *Harauz and Chiu* 38 (1991) 305
Image processing in TEM using the wavelet transform, *Beltrán del Río, Gómez and José-Yacamán* 38 (1991) 319

Imaging
Optimum focus for taking electron holograms, *Lichte* 38 (1991) 13
Phase contrast from a regular stacking of equally sized iron-oxide spheres, *Bentzon and Thölén* 38 (1991) 105
Theory of phase correlations in localized inelastic electron diffraction and imaging, *Wang and Bentley* 38 (1991) 181

Instrumentation
Performance of electron image converters with YAG single-crystal screen and CCD sensor, *Daberkow, Herrmann, Liu and Rau* 38 (1991) 215
Development of a superfluid helium stage for high-resolution electron microscopy, *Fujiyoshi, Mizusaki, Morikawa, Yamagishi, Aoki, Kihara and Harada* 38 (1991) 241

Elsevier Science Publishers B.V.

Methods and techniques
Optimum focus for taking electron holograms, *Lichte* 38 (1991) 13
A fast algorithm for transposing large multidimensional image data sets, *Van Heel* 38 (1991) 75
Displacement field analysis: calculation of distortion measures from displacement maps, *Dürr* 38 (1991) 135
Small-angle cleavage of semiconductors for transmission electron microscopy, *McCaffrey* 38 (1991) 149
Towards a practical method for EELS quantification, *Hofer and Luo* 38 (1991) 159
Improved methods for the determination of the spherical aberration coefficient in high resolution electron microscopy from micrographs of an amorphous object, *Coene and Denteneer* 38 (1991) 225
Measurement of the spherical aberration coefficient of transmission electron microscopes by beam-tilt-induced image displacements, *Koster and De Jong* 38 (1991) 235
New methods for qualitative and quantitative analysis of the GaAs/AlGaAs interface by high-resolution electron microscopy, *Thoma and Cerva* 38 (1991) 265

New developments
Electron crystallography at atomic resolution: ab initio structure analysis of copper perchlorophthalocyanine, *Dorset, Tivol and Turner* 38 (1991) 41
Electron energy-loss spectrum-imaging, *Hunt and Williams* 38 (1991) 47
A protocol for 3D image reconstruction from a single image of an oblique section, *Taylor and Crowther* 38 (1991) 85
Electron Compton scattering with parallel detection: an experiment with very low count rates, *Jonas and Schattschneider* 38 (1991) 117
Improved methods for the determination of the spherical aberration coefficient in high resolution electron microscopy from micrographs of an amorphous object, *Coene and Denteneer* 38 (1991) 225
Measurement of the spherical aberration coefficient of transmission electron microscopes by beam-tilt-induced image displacements, *Koster and De Jong* 38 (1991) 235
Development of a superfluid helium stage for high-resolution electron microscopy, *Fujiyoshi, Mizusaki, Morikawa, Yamagishi, Aoki, Kihara and Harada* 38 (1991) 241
Electrochemically induced adsorption of radio-labeled DNA on gold and HOPG substrates for STM investigations, *Brown, Allison, Warmack, Jacobson, Larimer, Woychik and Carrier* 38 (1991) 253
New methods for qualitative and quantitative analysis of the GaAs/AlGaAs interface by high-resolution electron microscopy, *Thoma and Cerva* 38 (1991) 265
Scanned-tip reflection-mode near-field scanning optical microscopy, *Cline, Barhatzky and Isaacson* 38 (1991) 299

Radiation damage and contamination
Electron-beam-induced transformations of gold particles epitaxially grown on MgO microcubes, *Giorgio, Henry, Chapon, Nihoul and Penisson* 38 (1991) 1

Scanning transmission electron microscopy
Energy-filtered convergent-beam electron diffraction in STEM, *Xu, Loane and Silcox* 38 (1991) 127
Utilization of STEM nanodiffraction data, *Konnert and D'Antonio* 38 (1991) 169

Scanning tunneling microscopy
Electrochemically induced adsorption of radio-labeled DNA on gold and HOPG substrates for STM investigations, *Brown, Allison, Warmack, Jacobson, Larimer, Woychik and Carrier* 38 (1991) 253
Scanned-tip reflection-mode near-field scanning optical microscopy, *Cline, Barhatzky and Isaacson* 38 (1991) 299

Specimen preparation
Small-angle cleavage of semiconductors for transmission electron microscopy, *McCaffrey* 38 (1991) 149
Preparation and detection of reconstructed plan-view surfaces, *Dunn, Ai, Savage, Zhang and Marks* 38 (1991) 333

Surfaces, clusters, interfaces and particles
Electron-beam-induced transformations of gold particles epitaxially grown on MgO microcubes, *Giorgio, Henry, Chapon, Nihoul and Penisson* 38 (1991) 1
Rigor, and plan-view simulation of surfaces, *Marks* 38 (1991) 325
Preparation and detection of reconstructed plan-view surfaces, *Dunn, Ai, Savage, Zhang and Marks* 38 (1991) 333
Validity of the kinematical approximation in transmission electron diffraction for surfaces, revisited, *Marks, Savage, Zhang and Ai* 38 (1991) 343

Thick specimens
Validity of the kinematical approximation in transmission electron diffraction for sur-

faces, revisited, *Marks, Savage, Zhang and Ai* 38 (1991) 343
EELS of "thick" specimens, *Egerton, Wang and Chen* 38 (1991) 349

Abstracts / Announcements / Book reviews / Comments / Editorials / Reports
New books and journals, *Hawkes* 38 (1991) 353
Report of a meeting, *Leapman* 38 (1991) 361